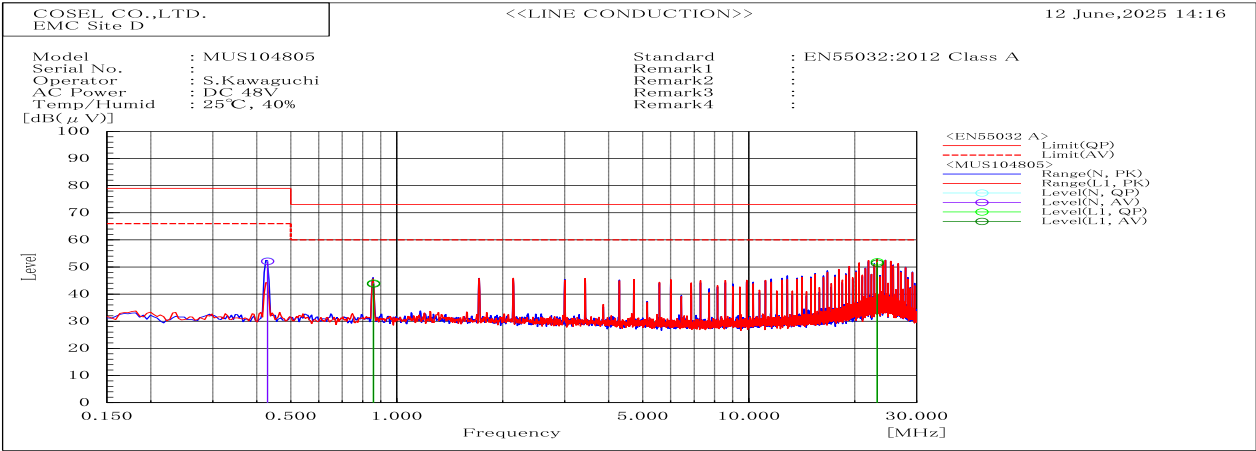
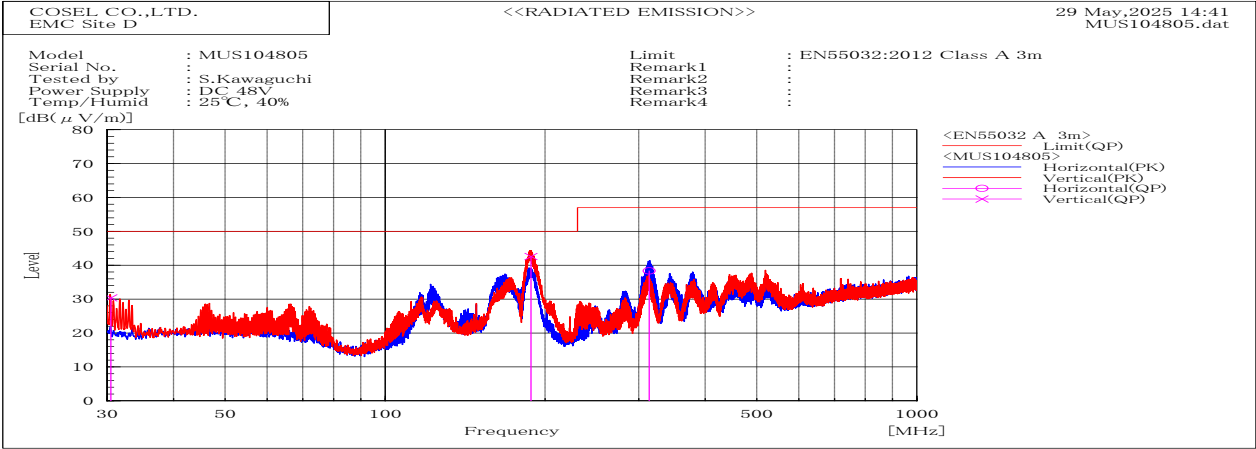


DATA SHEET		Date	12-Jun-25
Model	MUS104805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



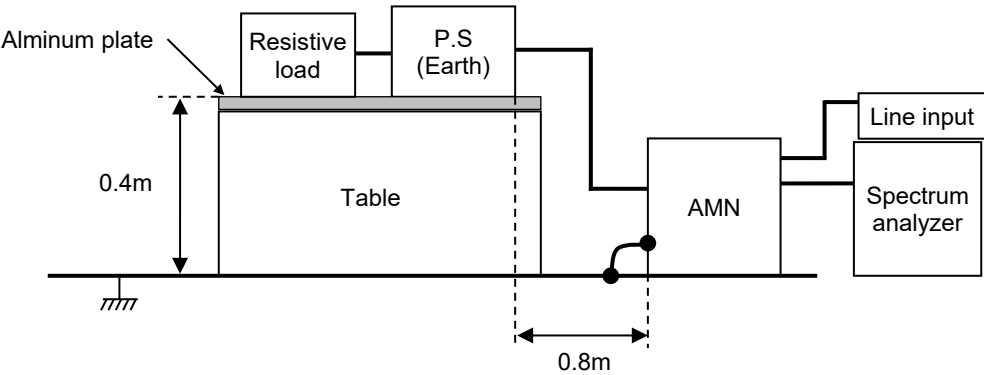
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
23.189	L1	51.9	51.4	73	60	21.1	8.6	Pass	
0.859	L1	44	43.8	73	60	29	16.2	Pass	
0.429	N	52.3	52.1	79	66	26.7	13.9	Pass	



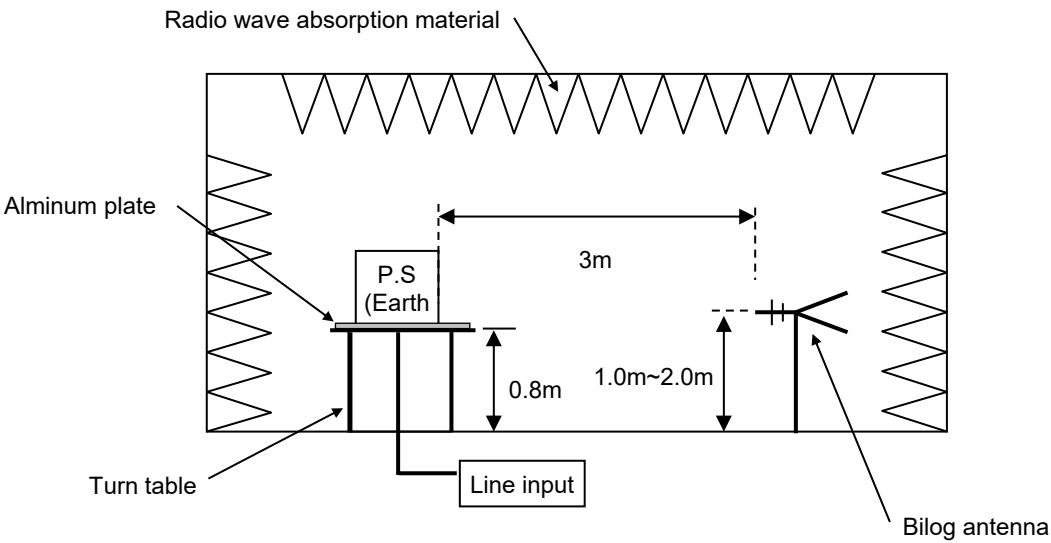
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m) QP	dB(uV/m) QP	dB QP				
187.994	V	Stable	42.6	50	7.4	Pass	100	355.5	
30.476	V	Stable	30.4	50	19.6	Pass	100.2	241.3	
313.681	H	Stable	38.3	57	18.7	Pass	110.3	242	

DATA SHEET		Date	12-Jun-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

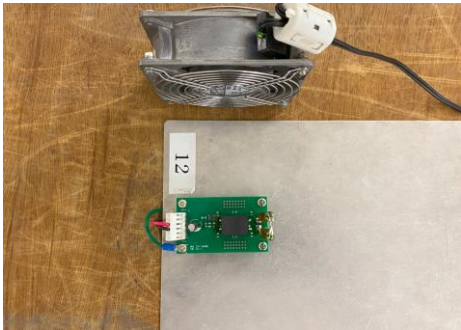
Test : EMI  
Model Name: MUS10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

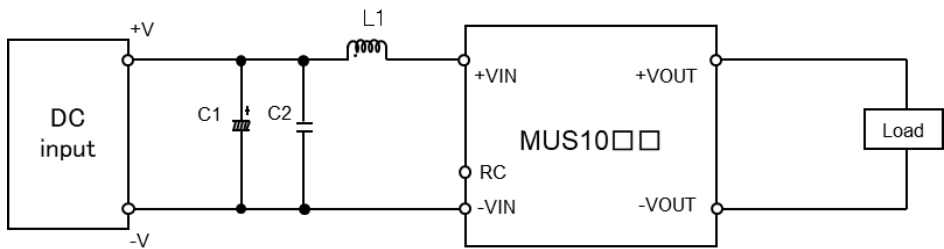


Fig.1 MUS10□□ Testing circuitry

C1 :	MUS1005□	25V 1500 $\mu$ F	Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MUS1012□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS1024□	—	
	MUS1048□	—	
C2 :	MUS1005□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS1012□	25V 10 $\mu$ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS1024□	50V 4.7 $\mu$ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1048□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS1005□	5000mA 2.2 $\mu$ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS1012□	3500mA 4.7 $\mu$ H	Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING)
	MUS1024□	1600mA 22 $\mu$ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1048□	1100mA 47 $\mu$ H	Inductor(LQH5BPN470M38 MURATA MANUFACTURING)